

Features

- Fast read access time – 45ns
- Low-power CMOS operation
 - 100µA max standby
 - 20mA max active at 5MHz
- JEDEC standard packages
 - 28-lead PDIP
 - 32-lead PLCC
- 5V ± 10% supply
- High reliability CMOS technology
 - 2,000V ESD protection
 - 200mA latchup immunity
- Rapid programming algorithm – 100µs/byte (typical)
- CMOS- and TTL-compatible inputs and outputs
- Integrated product identification code
- Industrial and automotive temperature ranges
- Green (Pb/halide-free) packaging option

1. Description

The Atmel® AT27C256R is a low-power, high-performance, 262,144-bit, one-time programmable, read-only memory (OTP EPROM) organized as 32K by 8 bits. It requires only one 5V power supply in normal read mode operation. Any byte can be accessed in less than 45ns, eliminating the need for speed reducing WAIT states on high-performance microprocessor systems.

The Atmel scaled CMOS technology provides low active power consumption and fast programming. Power consumption is typically only 8mA in active mode and less than 10µA in standby mode.

The AT27C256R is available in a choice of industry-standard, JEDEC-approved, one-time programmable (OTP) PDIP and PLCC packages. All devices feature two-line control (\overline{CE} , \overline{OE}) to give designers the flexibility to prevent bus contention.

With 32K byte storage capability, the AT27C256R allows firmware to be stored reliably and to be accessed by the system without the delays of mass storage media.

The AT27C256R has additional features to ensure high quality and efficient production use. The rapid programming algorithm reduces the time required to program the part and guarantees reliable programming. Programming time is typically only 100µs/byte. The integrated product identification code electronically identifies the device and manufacturer. This feature is used by industry-standard programming equipment to select the proper programming algorithms and voltages.



256K (32K x 8)
One-time
Programmable,
Read-only Memory

Atmel AT27C256R



2. Pin configurations

Pin name	Function
A0 - A14	Addresses
O0 - O7	Outputs
\overline{CE}	Chip enable
\overline{OE}	Output enable
NC	No connect



Note: PLCC package pins 1 and 17 are "don't connect"

3. System considerations

Switching between active and standby conditions via the chip enable pin may produce transient voltage excursions. Unless accommodated by the system design, these transients may exceed datasheet limits, resulting in device non-conformance. At a minimum, a 0.1 μ F, high-frequency, low inherent inductance, ceramic capacitor should be utilized for each device. This capacitor should be connected between the V_{CC} and ground terminals of the device, as close to the device as possible. Additionally, to stabilize the supply voltage level on printed circuit boards with large EPROM arrays, a 4.7 μ F bulk electrolytic capacitor should be utilized, again connected between the V_{CC} and ground terminals. This capacitor should be positioned as close as possible to the point where the power supply is connected to the array.

Figure 3-1. Block diagram



4. Absolute maximum ratings*

Temperature under bias	-55°C to +125°C
Storage temperature	-65°C to +150°C
Voltage on any pin with respect to ground	-2.0V to +7.0V ⁽¹⁾
Voltage on A9 with respect to ground	-2.0V to +14.0V ⁽¹⁾
V _{pp} supply voltage with respect to ground	-2.0V to +14.0V ⁽¹⁾

*NOTICE: Stresses beyond those listed under “Absolute maximum ratings” may cause permanent damage to the device. This is a stress rating only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

Note: 1. Minimum voltage is -0.6V DC, which may undershoot to -2.0V for pulses of less than 20ns. Maximum output pin voltage is V_{CC} + 0.75V DC, which may overshoot to +7.0V for pulses of less than 20ns.

5. DC and AC characteristics

Table 5-1. Operating Modes

Mode/Pin	\overline{CE}	\overline{OE}	Ai	V _{PP}	Outputs
Read	V _{IL}	V _{IL}	Ai	V _{CC}	D _{OUT}
Output disable	V _{IL}	V _{IH}	X ⁽¹⁾	V _{CC}	High Z
Standby	V _{IH}	X ⁽¹⁾	X ⁽¹⁾	V _{CC}	High Z
Rapid program ⁽²⁾	V _{IL}	V _{IH}	Ai	V _{PP}	D _{IN}
PGM verify ⁽²⁾	X ⁽¹⁾	V _{IL}	Ai	V _{PP}	D _{OUT}
Optional PGM verify ⁽²⁾	V _{IL}	V _{IL}	Ai	V _{CC}	D _{OUT}
PGM inhibit ⁽²⁾	V _{IH}	V _{IH}	X ⁽¹⁾	V _{PP}	High Z
Product identification ⁽⁴⁾	V _{IL}	V _{IL}	A9 = V _H ⁽³⁾ A0 = V _{IH} or V _{IL} A1 - A14 = V _{IL}	V _{CC}	Identification code

Notes: 1. X can be V_{IL} or V_{IH}.
 2. Refer to programming characteristics.
 3. V_H = 12.0 ± 0.5V.
 4. Two identifier bytes may be selected. All Ai inputs are held low (V_{IL}), except A9, which is set to V_{IH}, and A0, which is toggled low (V_{IL}) to select the manufacturer’s identification byte and high (V_{IH}) to select the device code byte.

Table 5-2. DC and AC operating conditions for read operation

		Atmel AT27C256R	
		-45	-70
Operating temp. (case)	Ind.	-40°C - 85°C	-40°C - 85°C
	Auto.		-40°C - 125°C
V _{CC} supply		5V ± 10%	5V ± 10%

Table 5-3. DC and operating characteristics for read operation

Symbol	Parameter	Condition	Min	Max	Units	
I_{LI}	Input load current	$V_{IN} = 0V$ to V_{CC}	Ind.		± 1	μA
			Auto.		± 5	μA
I_{LO}	Output leakage current	$V_{OUT} = 0V$ to V_{CC}	Ind.		± 5	μA
			Auto.		± 10	μA
$I_{PP1}^{(2)}$	$V_{PP}^{(1)}$ read/standby current	$V_{PP} = V_{CC}$		10	μA	
I_{SB}	$V_{CC}^{(1)}$ standby current	I_{SB1} (CMOS), $\overline{CE} = V_{CC} \pm 0.3V$		100	μA	
		I_{SB2} (TTL), $\overline{CE} = 2.0$ to $V_{CC} + 0.5V$		1	mA	
I_{CC}	V_{CC} active current	$f = 5MHz$, $I_{OUT} = 0mA$, $\overline{E} = V_{IL}$		20	mA	
V_{IL}	Input low voltage		-0.6	0.8	V	
V_{IH}	Input high voltage		2.0	$V_{CC} + 0.5$	V	
V_{OL}	Output low voltage	$I_{OL} = 2.1mA$		0.4	V	
V_{OH}	Output high voltage	$I_{OH} = -400\mu A$	2.4		V	

- Notes:
- V_{CC} must be applied simultaneously with or before V_{PP} , and removed simultaneously with or after V_{PP} .
 - V_{PP} may be connected directly to V_{CC} , except during programming. The supply current would then be the sum of I_{CC} and I_{PP} .

Table 5-4. AC characteristics for read operation

Symbol	Parameter	Condition	Atmel AT27C256R				Units
			-45		-70		
			Min	Max	Min	Max	
$t_{ACC}^{(1)}$	Address to output delay	$\overline{CE} = \overline{OE} = V_{IL}$		45		70	ns
$t_{CE}^{(1)}$	\overline{CE} to output delay	$\overline{OE} = V_{IL}$		45		70	ns
$t_{OE}^{(1)}$	\overline{OE} to output delay	$\overline{CE} = V_{IL}$		20		30	ns
$t_{DF}^{(1)}$	\overline{OE} or \overline{CE} high to output float, whichever occurred first			20		25	ns
t_{OH}	Output hold from address, \overline{CE} or \overline{OE} , whichever occurred first		7		7		ns

- Note:
- See AC waveforms for read operation.

Figure 5-1. AC waveforms for read operation⁽¹⁾

- Notes:
1. Timing measurement reference level is 1.5V for -45 devices. Input AC drive levels are $V_{IL} = 0.0V$ and $V_{IH} = 3.0V$. Timing measurement reference levels for all other speed grades are $V_{OL} = 0.8V$ and $V_{OH} = 2.0V$. Input AC drive levels are $V_{IL} = 0.45V$ and $V_{IH} = 2.4V$.
 2. \overline{OE} may be delayed up to $t_{CE} - t_{OE}$ after the falling edge of \overline{CE} without impact on t_{CE} .
 3. \overline{OE} may be delayed up to $t_{ACC} - t_{OE}$ after the address is valid without impact on t_{ACC} .
 4. This parameter is only sampled, and is not 100% tested.
 5. Output float is defined as the point when data is no longer driven.

Figure 5-2. Input test waveforms and measurement levels

For -45 devices only:



For -70 devices:

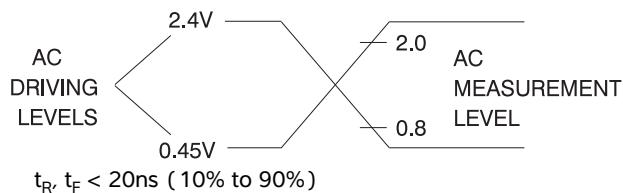
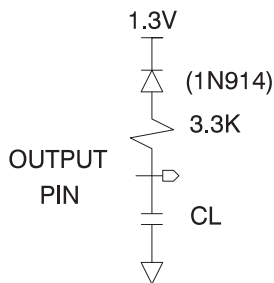


Figure 5-3. Output test load



Note: 1. $C_L = 100\text{pF}$ including jig capacitance, except for the -45 devices, where $C_L = 30\text{pF}$.

Table 5-5. Pin capacitance

$f = 1\text{MHz}$, $T = 25^\circ\text{C}$ ⁽¹⁾

Symbol	Typ	Max	Units	Conditions
C_{IN}	4	6	pF	$V_{IN} = 0\text{V}$
C_{OUT}	8	12	pF	$V_{OUT} = 0\text{V}$

Note: 1. Typical values for nominal supply voltage. This parameter is only sampled, and is not 100% tested.

Figure 5-4. Programming Waveforms⁽¹⁾



- Notes:
1. The input timing reference is 0.8V for V_{IL} and 2.0V for V_{IH} .
 2. t_{OE} and t_{DFP} are characteristics of the device, but must be accommodated by the programmer.
 3. When programming the Atmel AT27C256R, a 0.1 μF capacitor is required across V_{PP} and ground to suppress spurious voltage transients.

Table 5-6. DC programming characteristics

 $T_A = 25 \pm 5^\circ\text{C}$, $V_{CC} = 6.5 \pm 0.25\text{V}$, $V_{PP} = 13.0 \pm 0.25\text{V}$

Symbol	Parameter	Test Conditions	Limits		Units
			Min	Max	
I_{LI}	Input load current	$V_{IN} = V_{IL}, V_{IH}$		± 10	μA
V_{IL}	Input low level		-0.6	0.8	V
V_{IH}	Input high level		2.0	$V_{CC} + 1$	V
V_{OL}	Output low volt	$I_{OL} = 2.1\text{mA}$		0.4	V
V_{OH}	Output high volt	$I_{OH} = -400\mu\text{A}$	2.4		V
I_{CC2}	V_{CC} supply current (program and verify)			25	mA
I_{PP2}	V_{PP} current	$\overline{CE} = V_{IL}$		25	mA
V_{ID}	A9 product identification voltage		11.5	12.5	V

Table 5-7. AC programming characteristics

 $T_A = 25 \pm 5^\circ\text{C}$, $V_{CC} = 6.5 \pm 0.25\text{V}$, $V_{PP} = 13.0 \pm 0.25\text{V}$

Symbol	Parameter	Test conditions ⁽¹⁾	Limits		Units
			Min	Max	
t_{AS}	Address setup time	Input rise and fall times (10% to 90%) 20ns	2		μs
t_{OES}	\overline{OE} setup time		2		μs
t_{DS}	Data setup time		2		μs
t_{AH}	Address hold time	Input pulse levels 0.45V to 2.4V	0		μs
t_{DH}	Data hold time		2		μs
t_{DFP}	\overline{OE} high to output float delay ⁽²⁾		0	130	ns
t_{VPS}	V_{PP} setup time	Input timing reference level 0.8V to 2.0V	2		μs
t_{VCS}	V_{CC} setup time		2		μs
t_{PW}	\overline{CE} program pulse width ⁽³⁾	Output timing reference level 0.8V to 2.0V	95	105	μs
t_{OE}	Data valid from \overline{OE} ⁽²⁾			150	ns
t_{PRT}	V_{PP} pulse rise time during programming		50		ns

- Notes:
- V_{CC} must be applied simultaneously with or before V_{PP} and removed simultaneously with or after V_{PP} .
 - This parameter is only sampled, and is not 100% tested. Output float is defined as the point where data is no longer driven. See timing diagram.
 - Program pulse width tolerance is $100\mu\text{s} \pm 5\%$.

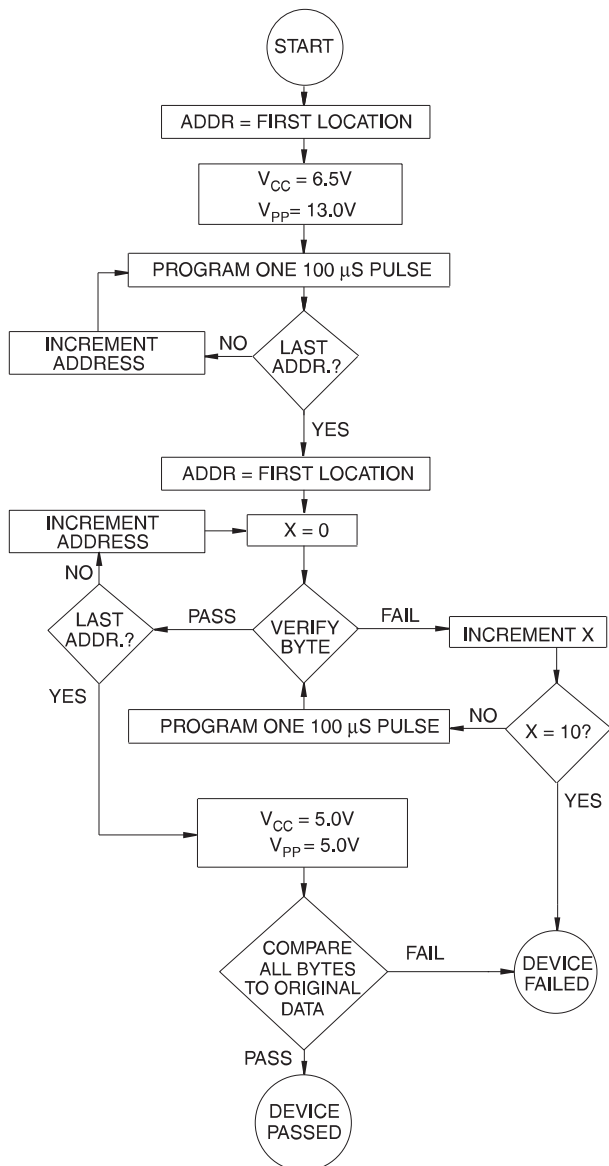
Table 5-8. The Atmel AT27C256R integrated product identification code

Codes	Pins									Hex data
	A0	O7	O6	O5	O4	O3	O2	O1	O0	
Manufacturer	0	0	0	0	1	1	1	1	0	1E
Device type	1	1	0	0	0	1	1	0	0	8C

6. Rapid programming algorithm

A $100\mu\text{s}$ $\overline{\text{CE}}$ pulse width is used to program. The address is set to the first location. V_{CC} is raised to 6.5V and V_{PP} is raised to 13.0V. Each address is first programmed with one $100\mu\text{s}$ $\overline{\text{CE}}$ pulse without verification. Then a verification/reprogramming loop is executed for each address. In the event a byte fails to pass verification, up to 10 successive $100\mu\text{s}$ pulses are applied with a verification after each pulse. If the byte fails to verify after 10 pulses have been applied, the part is considered failed. After the byte verifies properly, the next address is selected until all have been checked. V_{PP} is then lowered to 5.0V and V_{CC} to 5.0V. All bytes are read again and compared with the original data to determine if the device passes or fails.

Figure 6-1. Rapid programming algorithm



7. Ordering information

Green package (Pb/halide-free)

t_{ACC} (ns)	I_{CC} (mA)		Atmel ordering code	Package	Lead finish	Operation range
	Active	Standby				
45	20	0.1	AT27C256R-45JU	32J	Matte tin	Industrial (-40°C to 85°C)
			AT27C256R-45PU	28P6	Matte tin	
70	20	0.1	AT27C256R-70JU	32J	Matte tin	Industrial (-40°C to 85°C)
			AT27C256R-70PU	28P6	Matte tin	

Package type	
32J	32-lead, plastic, J-leaded chip carrier (PLCC)
28P6	28-lead, 0.600" wide, plastic, dual inline package (PDIP)

8. Packaging information

32J – PLCC



28P6 – PDIP





9. Revision history

Doc. rev.	Date	Comments
0014O	10/2011	Correct pinouts
0014N	04/2011	Remove TSOP and SOIC packages Add lead finish to ordering information
0014M	12/2007	

